

# Electrostatically-Reversible Polarity of Dual-Gated Graphene Transistors

**Shu Nakaharai**

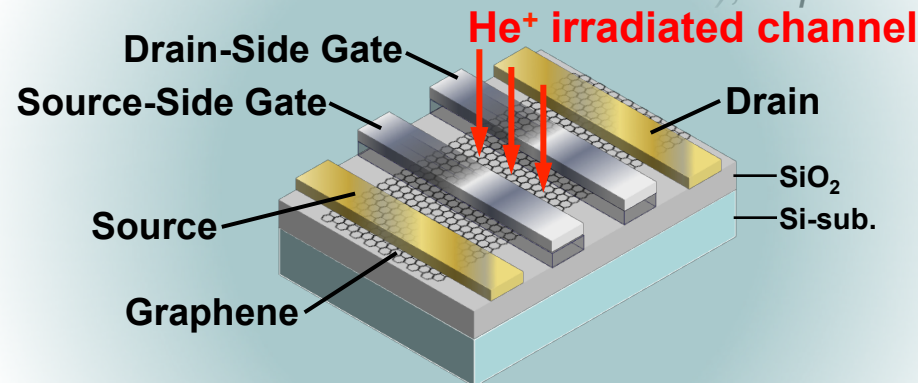
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# Outline

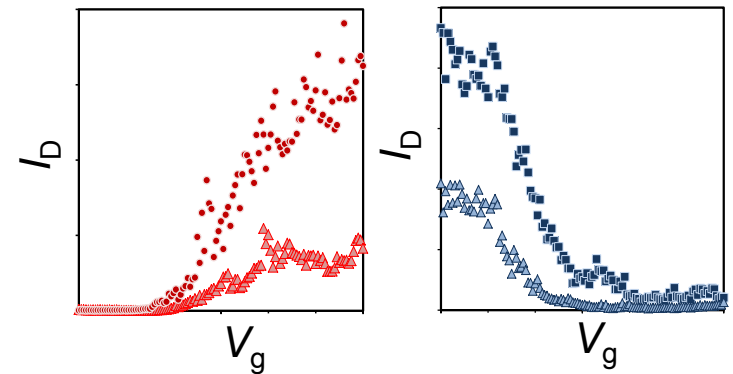
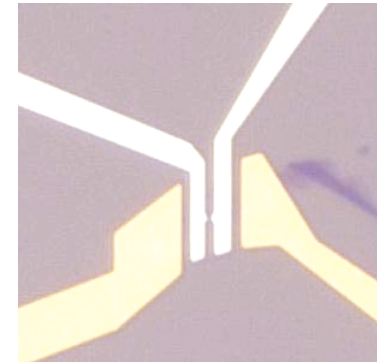
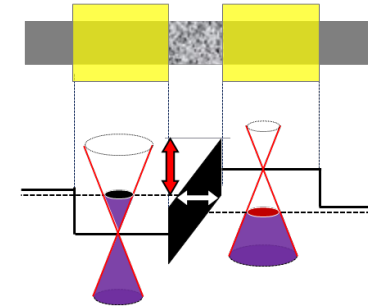
0. Introduction

1. Device Concept

2. Device Fabrication

3. Device Operation

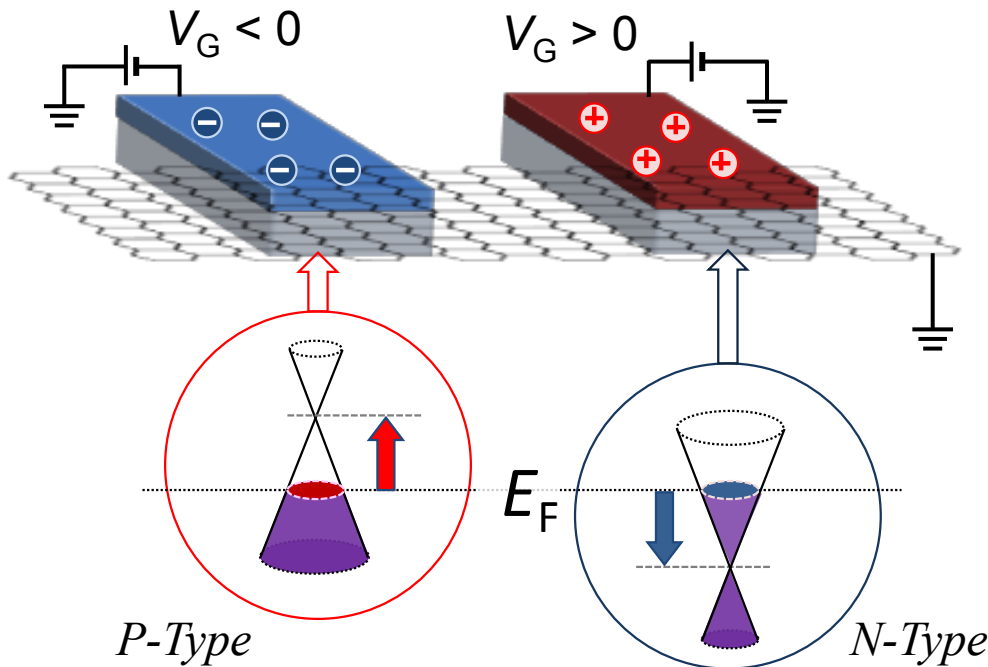
4. Summary



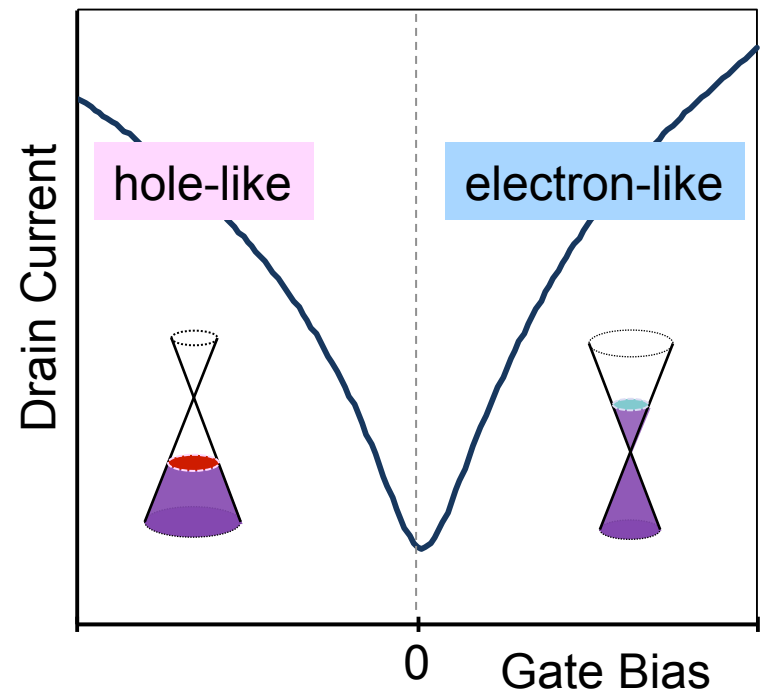
# Background — Why Graphene?

Advantages for polarity-reversible devices:

## Electrostatically-Reversible Polarity of Carriers



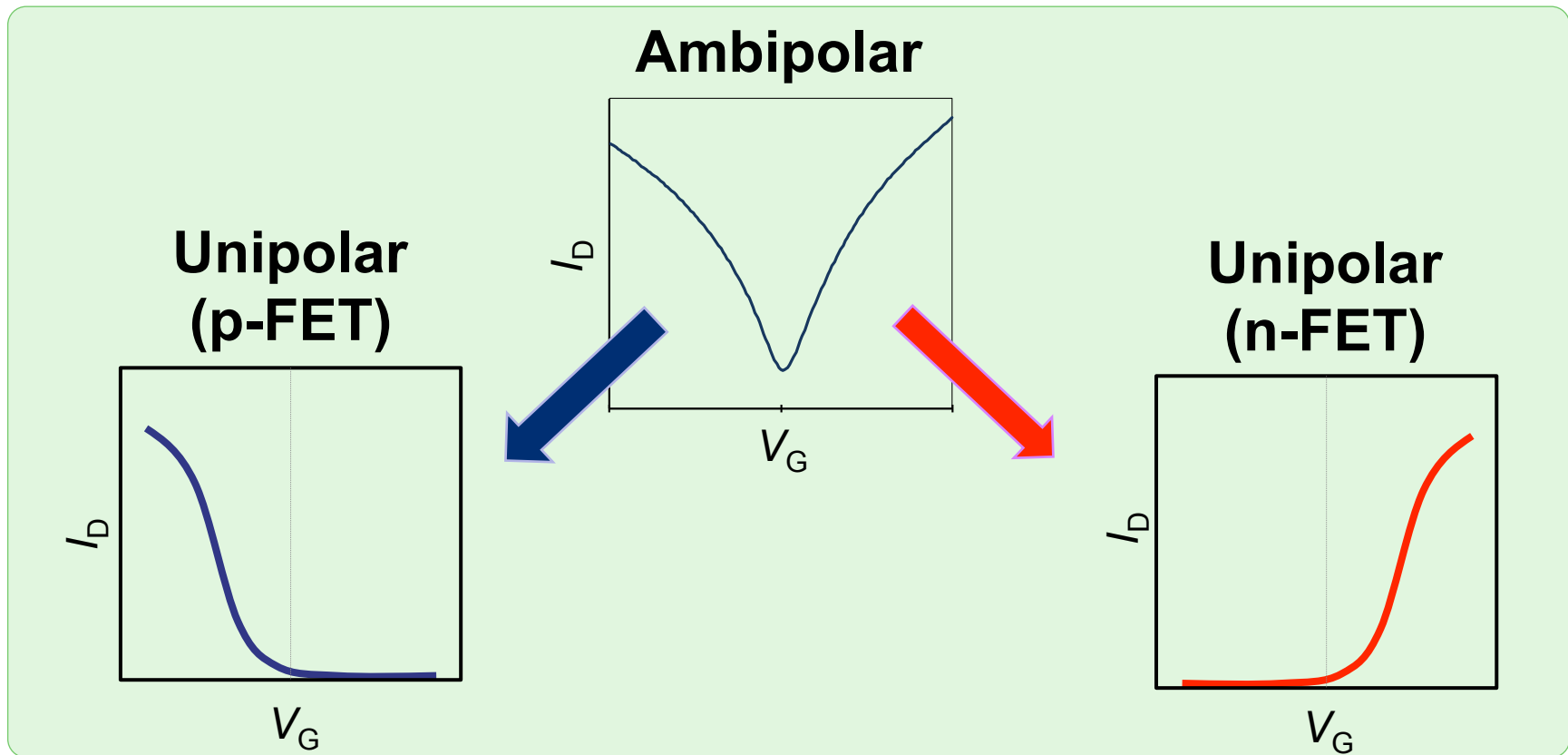
## Symmetric Conduction of Electrons and Holes



**Graphene is Ideal for Polarity-Reversible Transistors!**

# Issues

- Poor current on/off switching
- Ambipolar carrier conduction



# Objectives

- Improve on/off switching of current
- Demonstrate unipolar transistor operations with electrostatically-reversible polarity

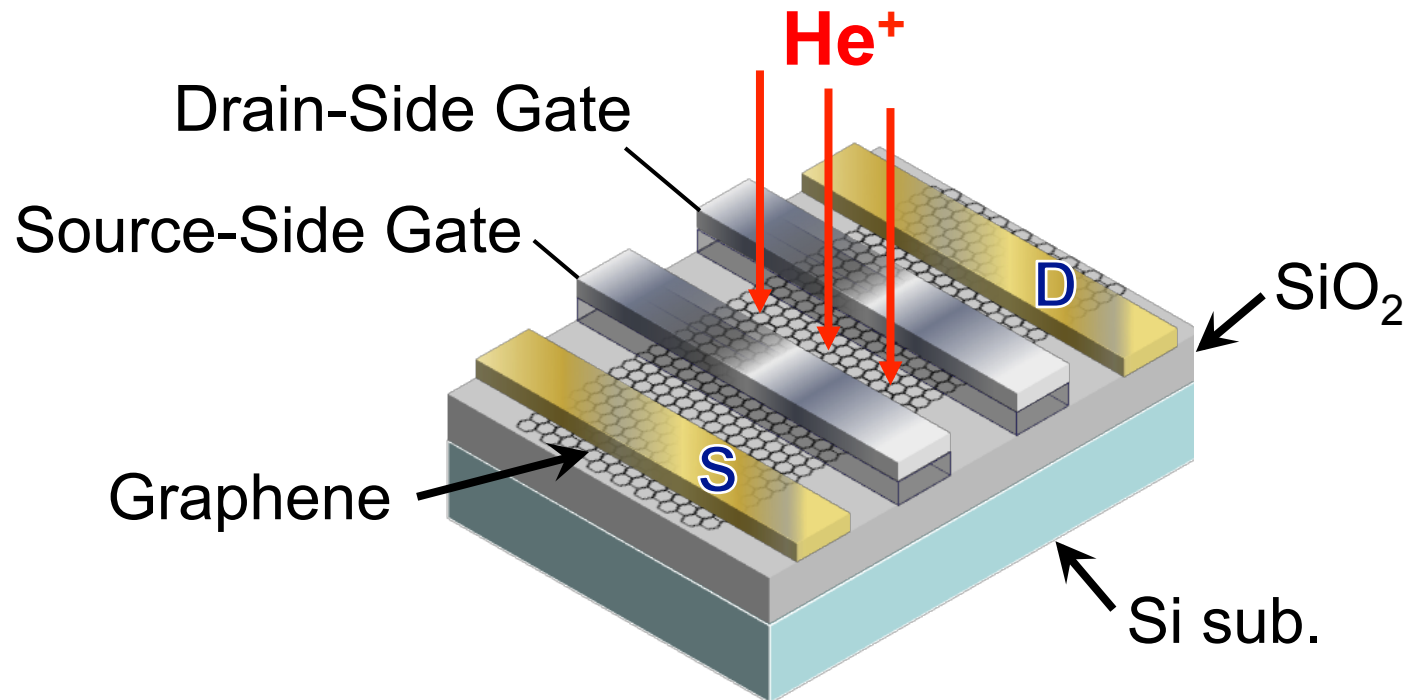
We propose a novel concept graphene transistor with...

- Gate-controlled P-I-N junction device structure
  - S. Nakaharai *et al.*, APEX **5**, 015101 (2012)
- He ion irradiated graphene channel
  - S. Nakaharai, *et al.*, Ext. Abst. SSDM **2012**, p676

# 1. Device Concept

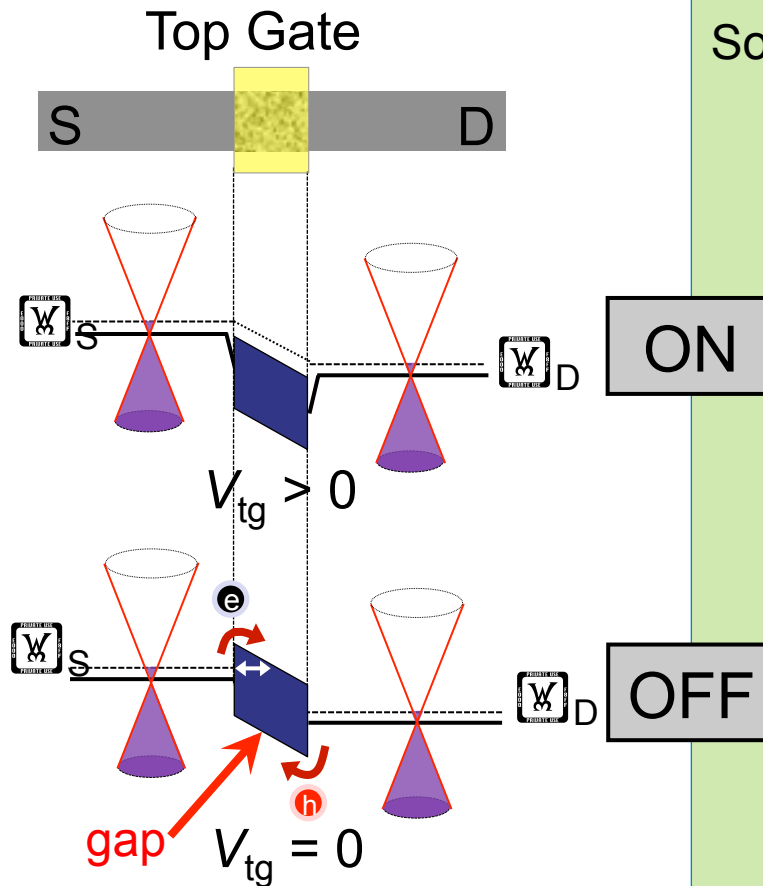
# Novel Device Structure

- Two top gates — Independent biasing
- Irradiation of He ion beam only between top gates
- Defect-induced transport gap opens



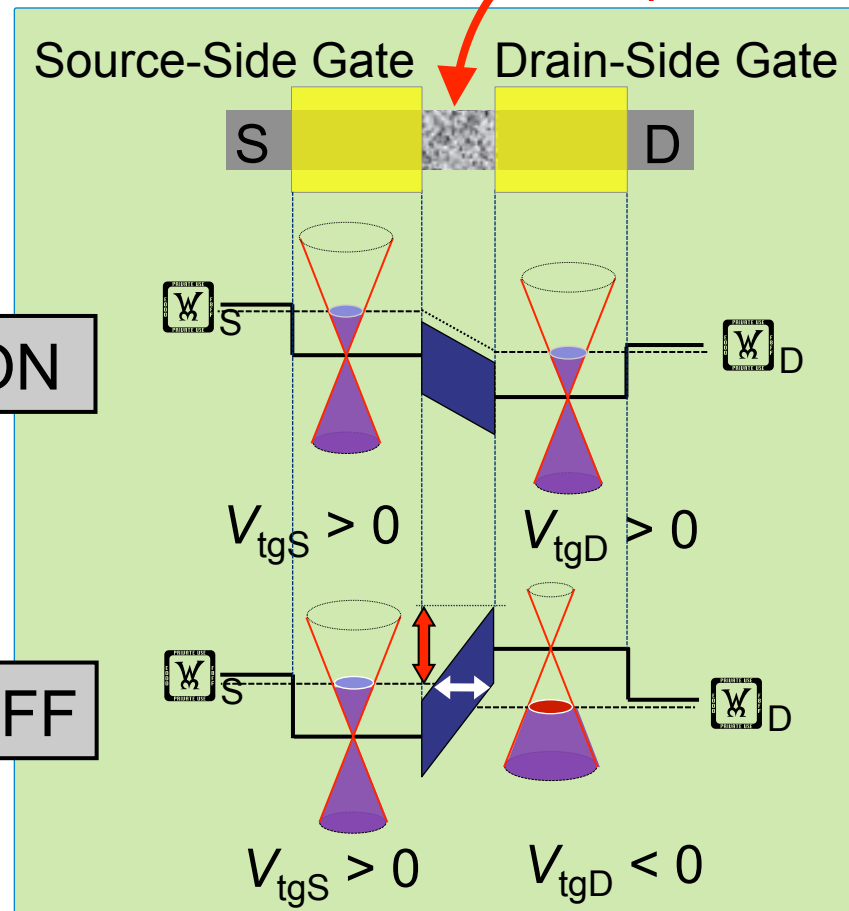
# Current On-Off Operation

Conventional Device



Novel Device

Ion Irradiated Graphene

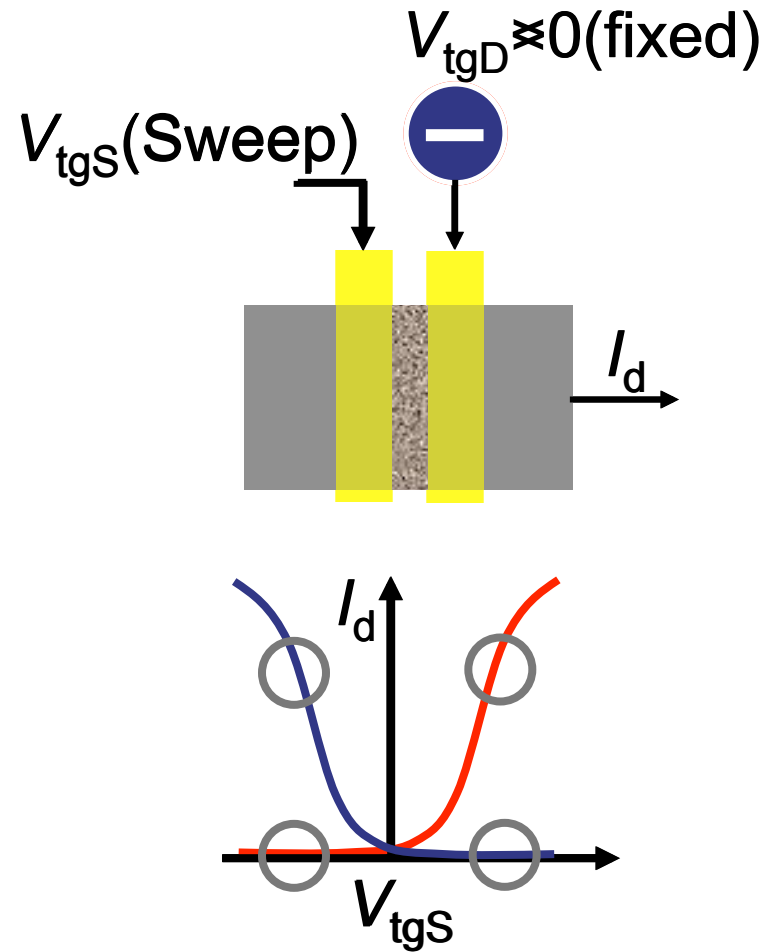
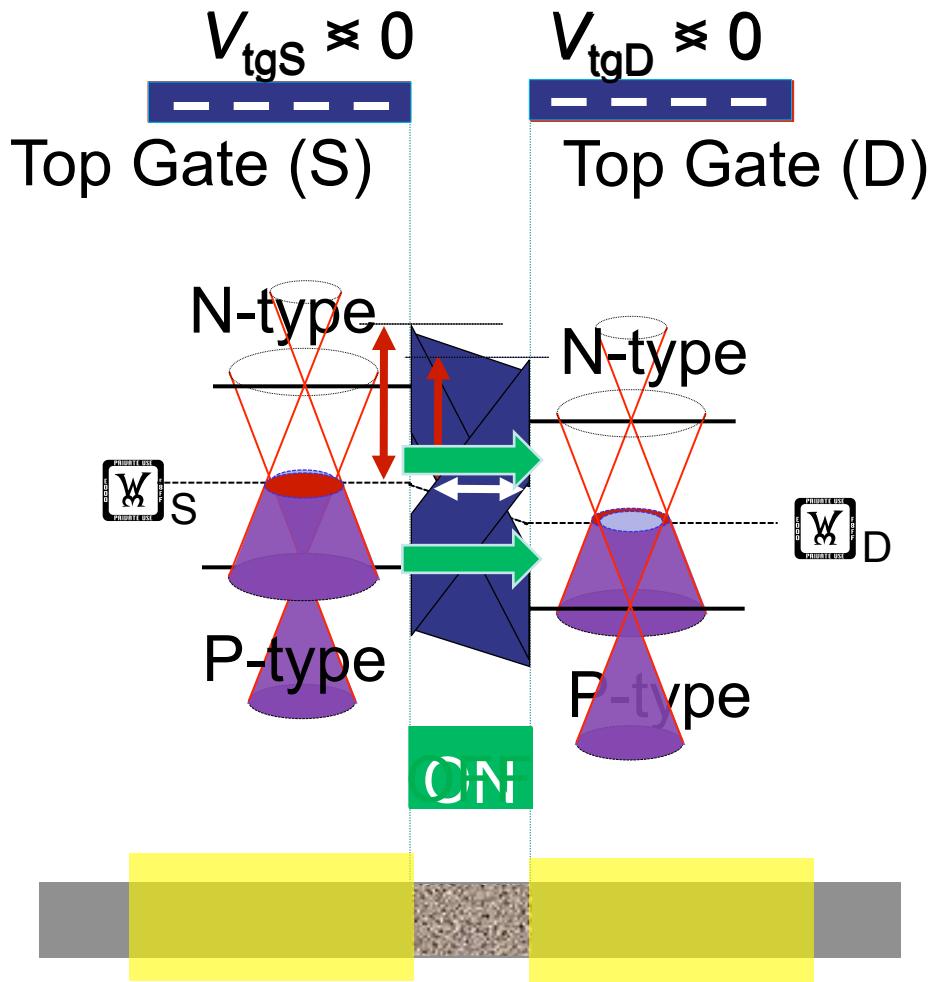


Better cut-off property!!



# Polarity-Reversible Operation

**nFET Mode**



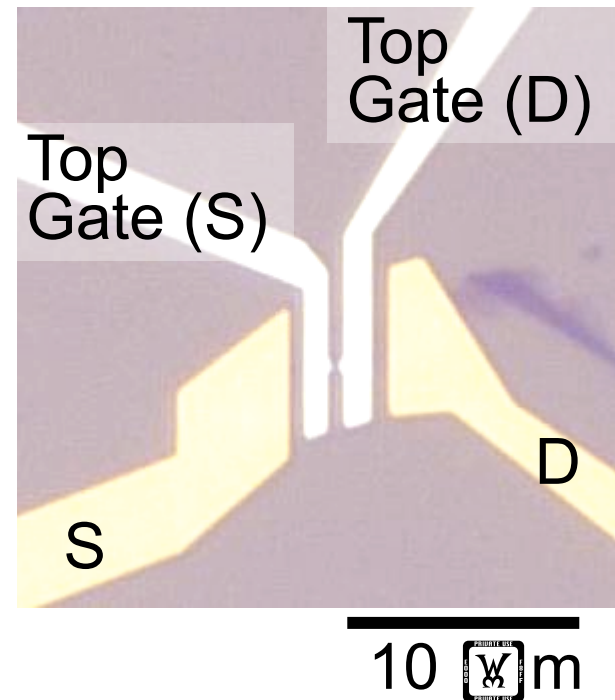
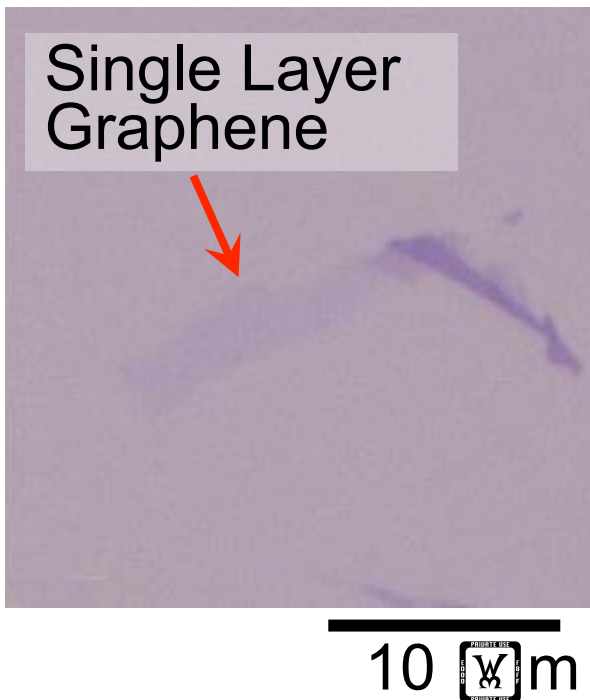
# Advantages of Novel Concept Device

- **Better on/off switching**
- **Unipolar, and electrostatically-reversible**
- **No impurity doping is needed.**
  - Free from dopant-related problems
- **CMOS-compatible fabrication process**
  - Only with “top-down” process

# 2. Device Fabrication

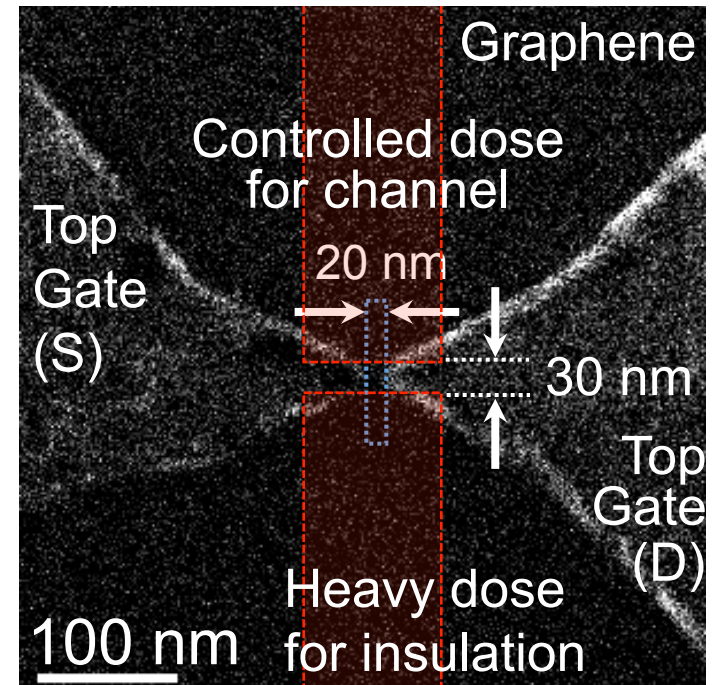
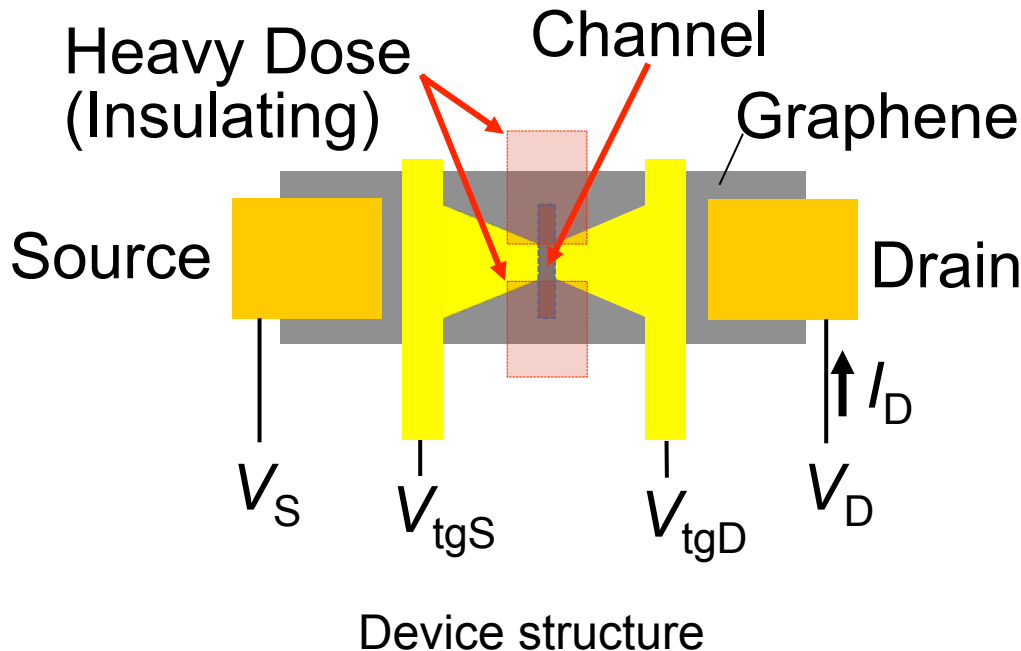
# Device Fabrication

- Mechanically-exfoliated single layer graphene was deposited on a 285-nm-thick  $\text{SiO}_2$  layer.
- Lift-off of contacts and top gates
  - Contact: Ti/Au; Top Gate:  $\text{SiO}_2/\text{Al}$



# Channel Fabrication

- He ion irradiation for “channel” at an ion dose of  $6.9 \times 10^{15}$  ions/cm<sup>2</sup>.
- Heavy dose makes graphene insulating.
- Channel size:  $L = 20$  nm,  $W = 30$  nm.



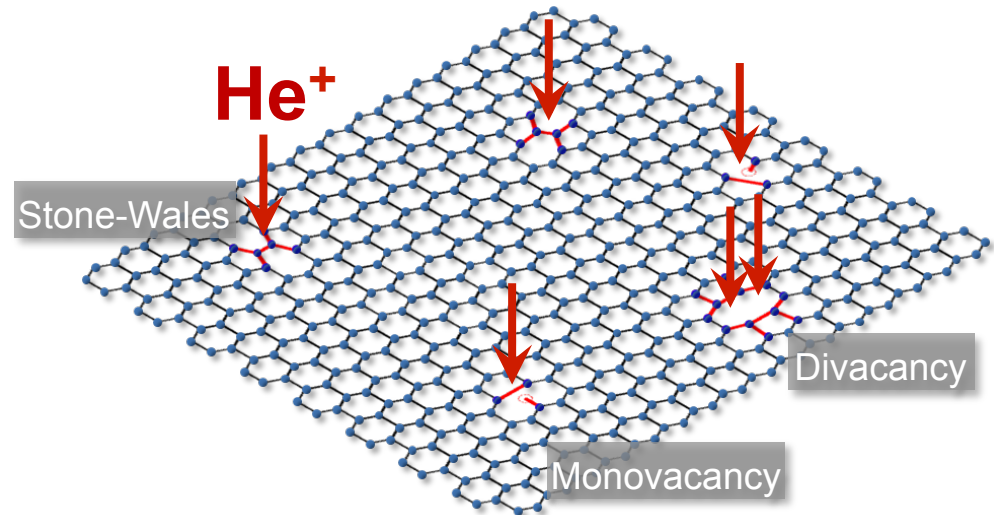
# He Ion Irradiated Graphene Channel

- Impact of He ions to graphene generates randomly distributed point defects.
- Defect-induced strong localization of carriers.
- Transport gap ( $\approx 380$  meV) enables conduction control in graphene by gate biasing.



Helium Ion Microscope (Carl Zeiss)

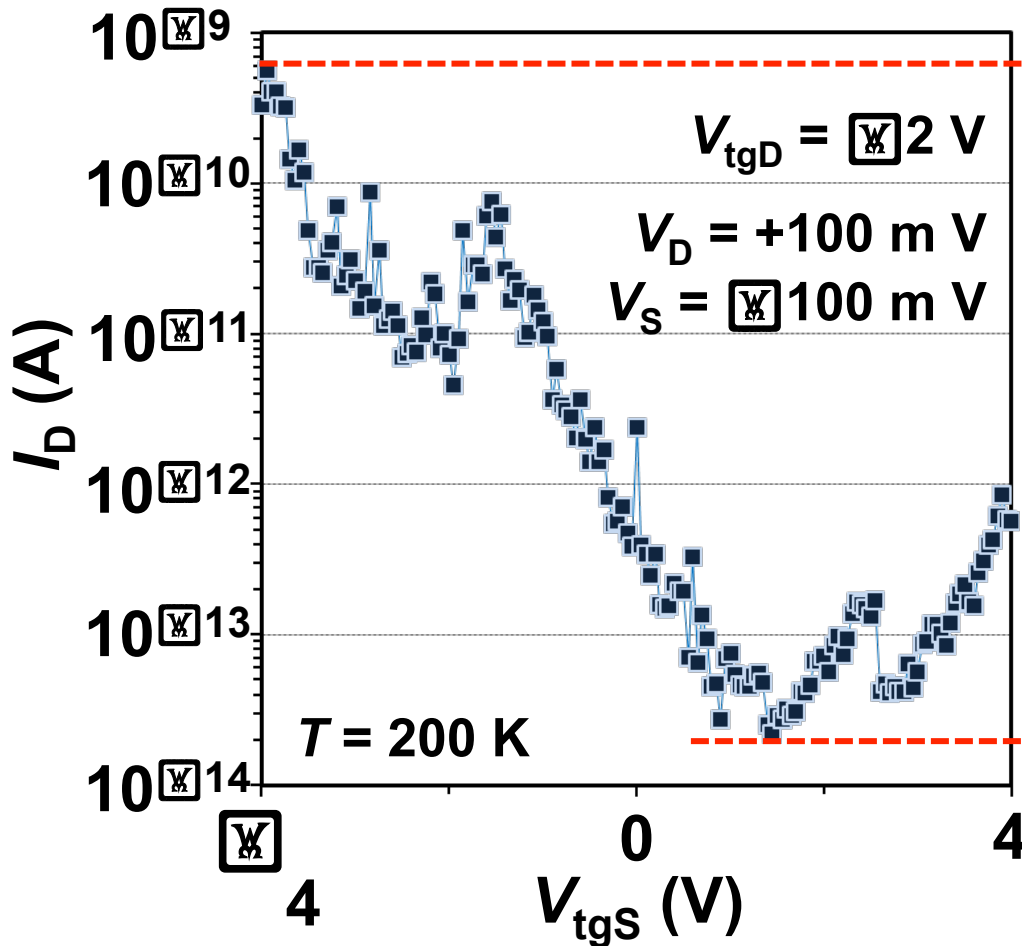
- $V_{\text{acc}} = 30$  kV
- Ion dose:  $1 \times 10^{15}$  to  $10^{16}$  ions/cm<sup>2</sup>
- Defect density : 0.1 % to 1 %



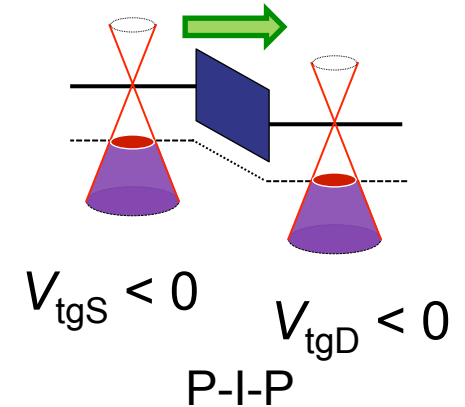
Graphene with 1% point defects

# 3. Device Operation

# On-Off Operation of Current

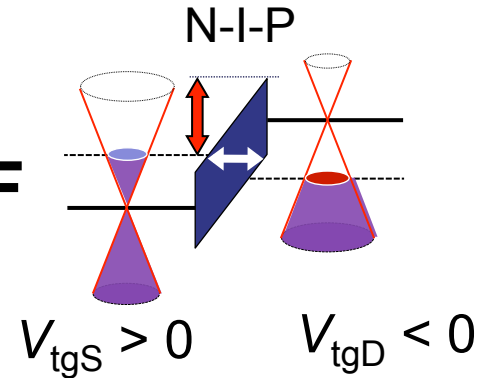


**ON**



**25400**

**OFF**

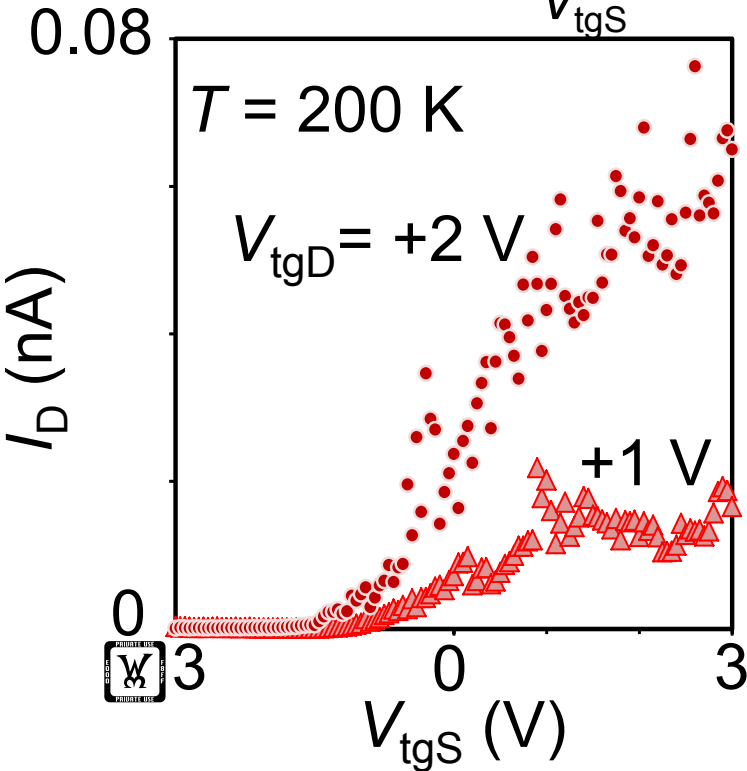
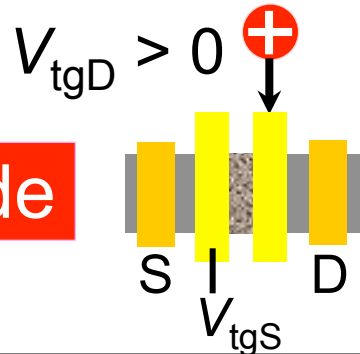


**On-Off ratio of 25400 was achieved at 200 K.**

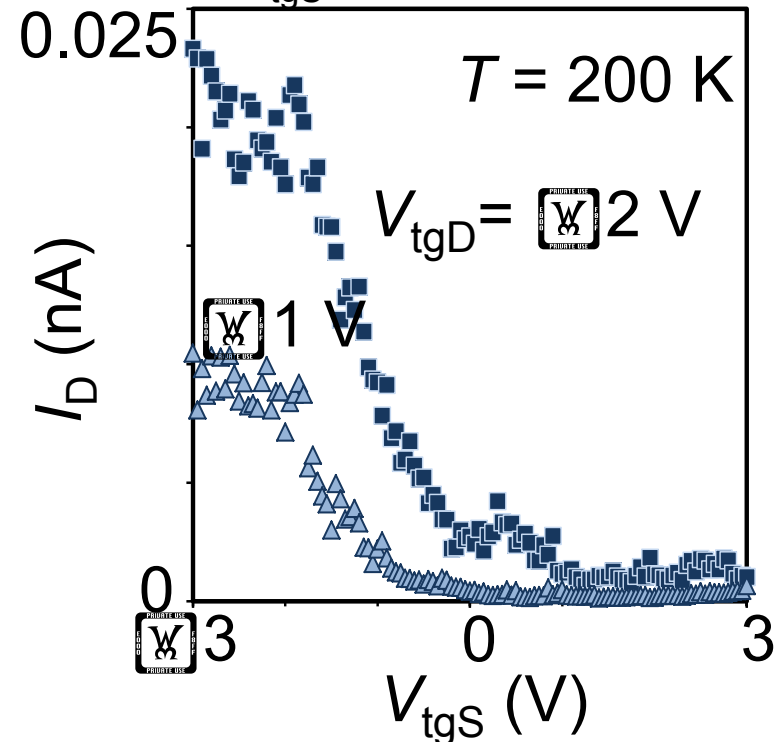
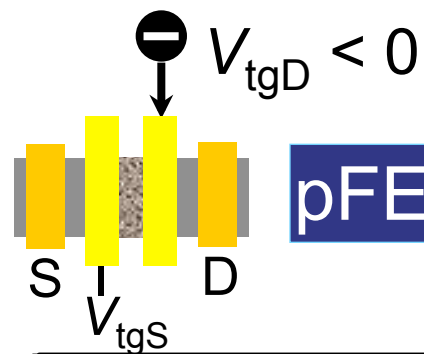


# Transistor Operations

**nFET Mode**



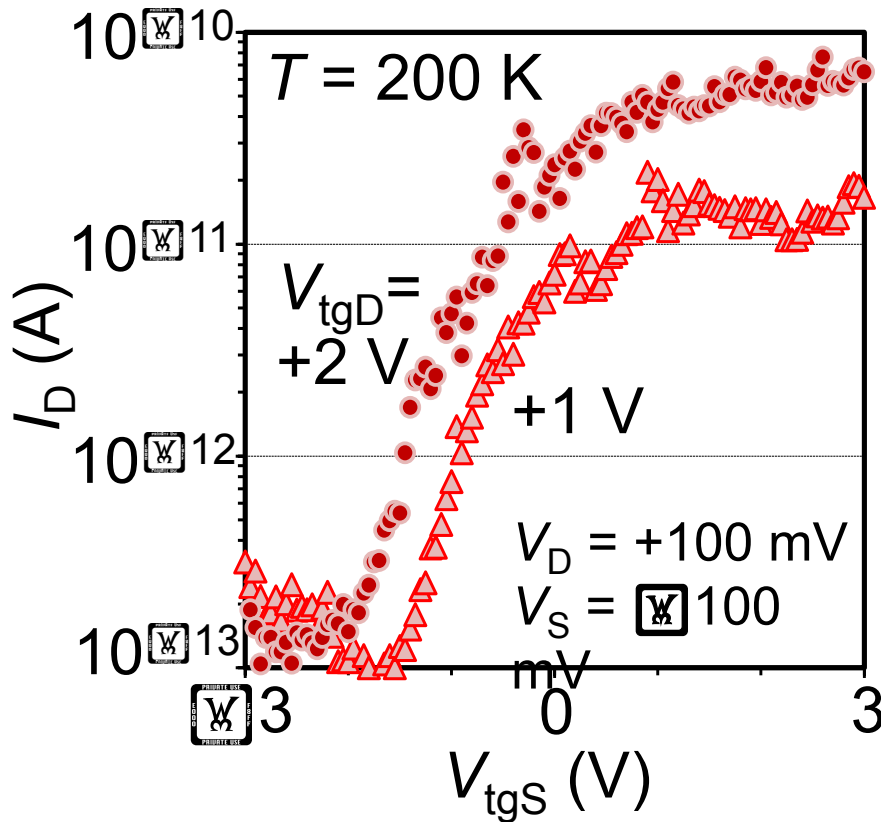
**pFET Mode**



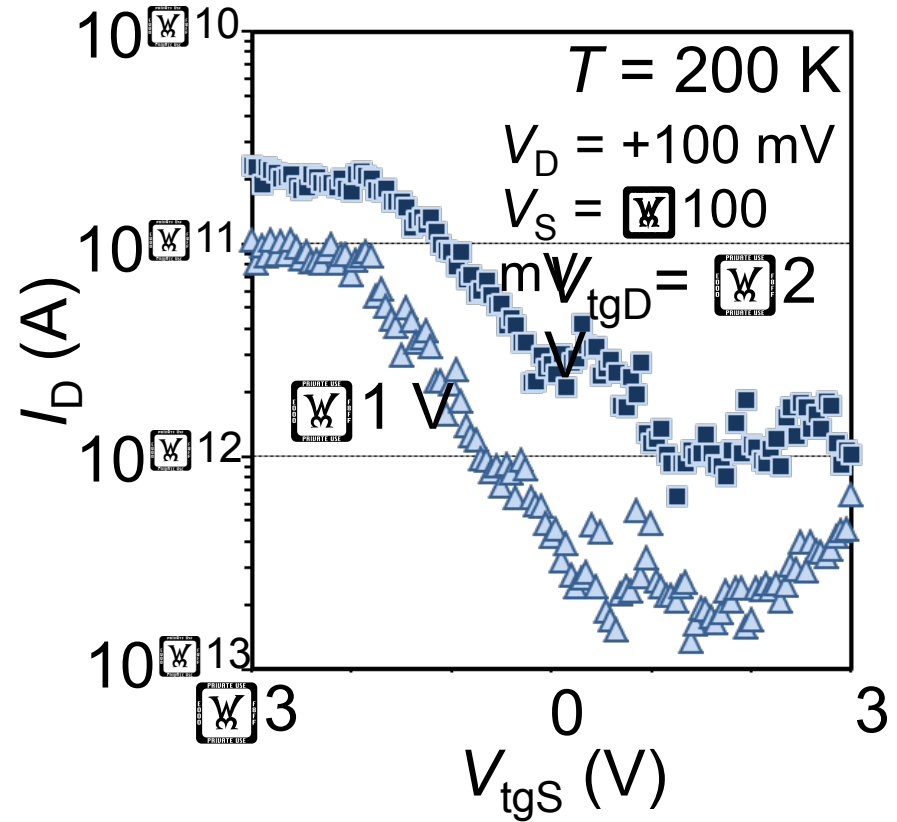
**Transistor polarity is reversible by a gate bias.**

# Transistor Operations (Logarithmic Scale)

nFET Mode



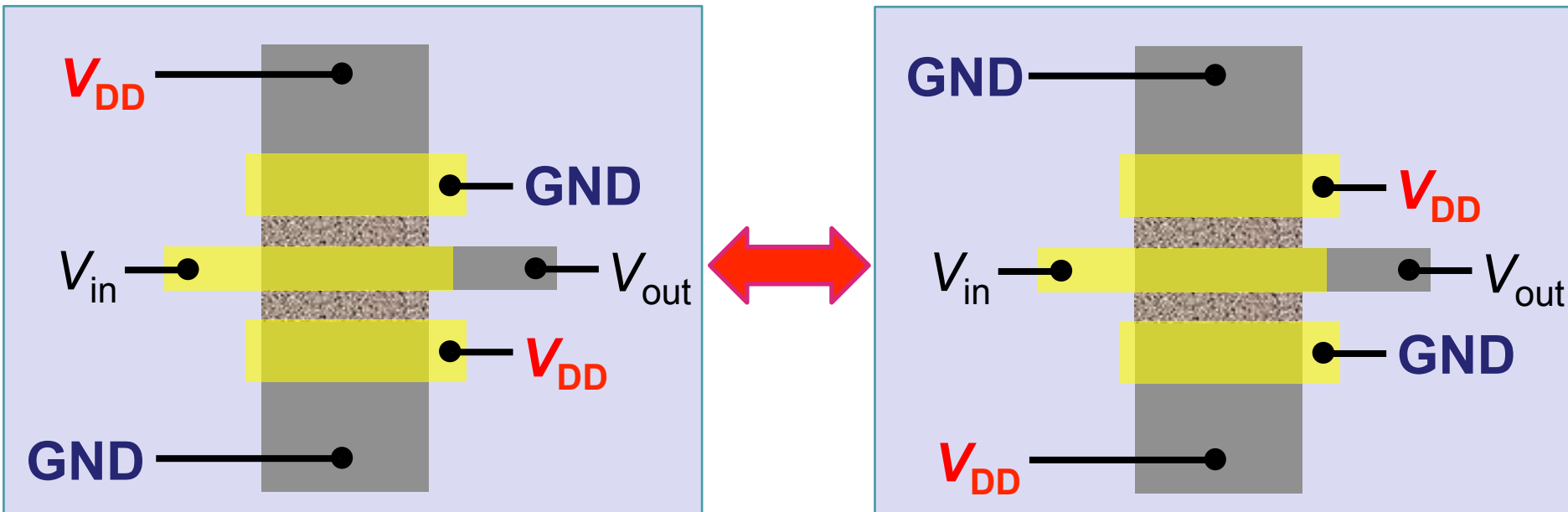
pFET Mode



**Transistor polarity is REVERSIBLE!**

# Electrostatically-Reconfigurable Circuit?

## Reversible Inverter



**Dynamic reconfiguration of circuit structure from the transistor level during computation is possible.**

# Summary

- **Novel concept graphene transistor with dual gates was proposed.**
- **Electrostatically-reversible transistor polarity was demonstrated.**
- **Dynamically-reconfigurable circuit is expected.**

For details: S. Nakaharai, *et al.*, Tech. Digest of IEDM **2012**, p.72

*Acknowledgement :*

This research is granted by JSPS through FIRST Program initiated by CSTP.

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